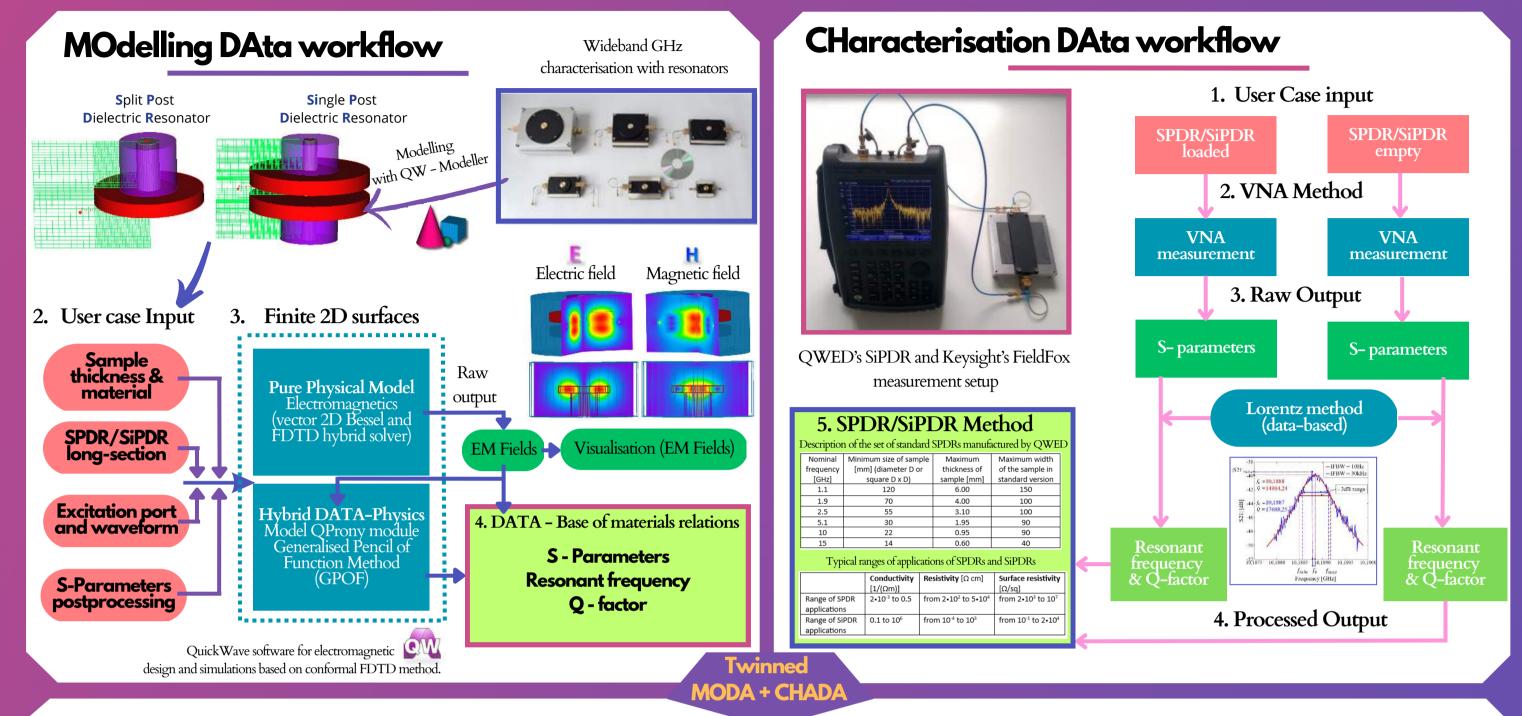


Twinned Modelling - Characterisation (MODA-CHADA) Solutions for Electronic and Energy Materials: from H2020 MMAMA and NanoBat to M-ERA.NET ULTCC6G_Epac and I4BAGS Projects

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...from H2020 MMAMA and NanoBat

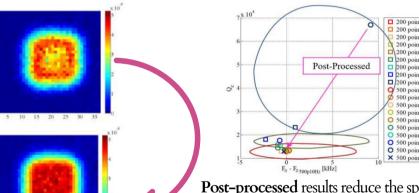
Nano (4) NanoBat aims to develop a novel RF-nanotechnology toolbox for quality testing of Li-ion and beyond Lithium batteries with the potential to redefine battery production in Europe and worldwide. A particular focus will be testing and quantifying the electrical processes at the SEI, which are responsible for battery performance and safety, but difficult to characterise and optimise. As SEI formation amounts to one thrid of battery production costs, the project will reduce such costs significantly and hence benefit the evolving clean energy and e-mobility transition in Europe.

lano (1) 10GHz Q-Meter

Implementation in the form of surface scanner for GHz-imaging of electronic and battery materials - Finalist of the European Innovation Radar Prize 2021.

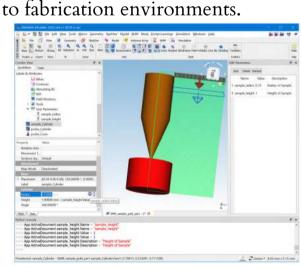


A photo of the imaging system built of the 2D SPDR scanner



Post-processed results reduce the spread of material parameters (compared to raw measurements), and reveal the actual losses (otherwise underestimated due to the noise)

The aim of this project is to accelerate the development of high efficiency cells and to have measures to predict performances in early stages prototype production. Where process monitoring of materials with nanostructures is necessary, dielectric resonator is used to translate insights from scanning microwave microscope measurements



licence-free CAD modellerfocus on User Cases relevant to SMM, dielectric resonator, and coaxial probe material measurements.

...to M-ERA.NET ULTCC6G_Epac and I4BAGS Projects

Measurement

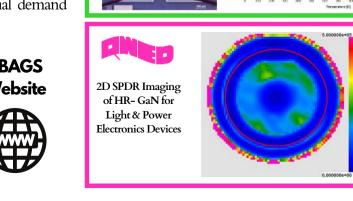
Loss tangent map f a 15 mm x 15 mm

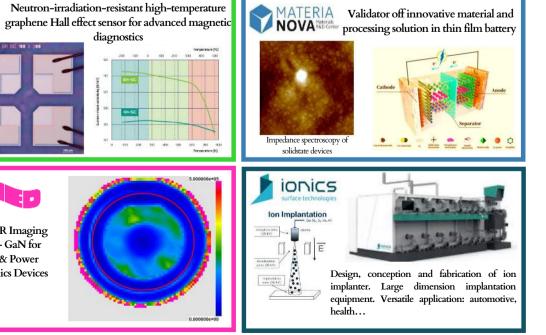
laminate SUT

The I4BAGS project aims to develop innovative processing solutions for characterisation microelectronics and battery applications. Driven by topical challenges in communication and energy management, and supported by large industrial demand for innovation.

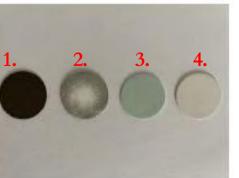








ULTCC6G_EPac



ULTCC Materials samples under investigation

main objective ULTCC6G_EPac is to develop novel functional materials based on advanced multilayer technology (ULTCC), characterise their properties dielectrical) and to demonstrate and validate the telecommunication devices based on the ULTCC6G EPac.

Sample name	Thickness [mm]	Dielectric constant	Loss tangent (±3%)
Sample 1	0.485 ± 0.015	5.40 ± 2.5%	0.00200 ±3%
Sample 2	0.64 ± 0.030	6.52 ± 4%	0.00233 ±3%
Sample 3	0.6 ± 0.030	5.12 ± 4%	0.00195 ±3%
Sample 4	0.55 ± 0.020	4.48 ± 3%	0.00328±3%



